


<b>Search Notes</b>  	<b>Application/Control No.</b>  10662917	<b>Applicant(s)/Patent Under Reexamination</b>  JAMI ET AL.
	<b>Examiner</b>  Ho, Huy C	<b>Art Unit</b>  2617

SEARCHED			
Class	Subclass	Date	Examiner
370	437	12/18/06	HH
	332	12/18/06	HH

SEARCH NOTES		
Search Notes	Date	Examiner
Applicant's IDS references were used in the Office Action	12/18/06	HH
EAST image and keyword search in USPATConclusion, US-PGPUB, USOCR, EPO, JPO, DERWENT, IBM_TDB (See attached search strategy)	5/8/07	HH
Search update	4/20/2009	HH
Search update	4/20/2009	HH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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